

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/822,761	ZHANG ET AL.	
Examiner	Art Unit	
Sean R. McGarry	1635	

	SEARCHED				
Class	Subclass	Date	Examiner		

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Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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